

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/041,685	SUEMATSU ET AL.	
	Examiner Yewebdar T Tadesse	Art Unit 1734	Page 1 of 1

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*	B	US-6,342,170	01-2002	Yang, Hsi-Hsing	264/1.25
*	C	US-6,347,890	02-2002	Ueno et al.	385/78
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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